

09/869274

JC18 Re CT/PTO 26 JUN 2001 of 2

#3

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
H-987

SERIAL NO.

LIST OF DOCUMENTS CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
A. NISHIMURA et alFILING DATE
June 26, 2001

GROUP

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
AA	AA	6,030,890	2/29/00	Iwabuchi			
AB	AB	6,008,543	12/28/99	Iwabuchi			
AC	AC	5,554,940	9/10/96	Hubacher			
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	4-26537	3/3/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM	4-96343	3/27/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN	5-218042	8/27/93	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AO	8-250498	9/27/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AP	8-64633	3/8/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR		IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.
AS		
AT		

EXAMINER

Miller-Dal

DATE CONSIDERED

12/10/02

09/869274

JC18 R001 PCT/PTO 26 JUN 2001 Sheet 2 of 2

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987		SERIAL NO.	
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	AA						
	AB						
	AC						
	AD						
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	AF						
	AG						
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		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
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	AL	8-340029	12/24/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AM	8-29451	2/2/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN						<input type="checkbox"/> <input type="checkbox"/>
	AO						<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
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EXAMINER				DATE CONSIDERED			
[Signature]				12/18/02			